

MRS BULLETIN

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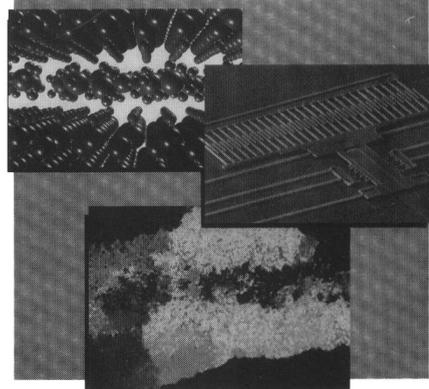
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Fundamentals of Friction



ON THE COVER: (Top) Molecular-dynamics simulation of a monolayer of liquid ethane molecules lubricating the interface between two hydrogen-terminated (111) diamond surfaces. Courtesy of J.A. Harrison and S.J. Stuart, based on their work at the United States Naval Academy. For more information, see the article by J.A. Harrison and S.S. Perry on p. 27 of this issue.

(Center) Scanning-electron-microscopy image of a friction test microstructure. Courtesy of R. Maboudian. For more information, see the article by R. Maboudian on p. 47 of this issue.

(Bottom) Molecular-dynamics simulation of two copper workpieces in sliding contact. Courtesy of J.E. Hammerberg. For more information, see the article by D.A. Rigney and J.E. Hammerberg on p. 32 of this issue.

(Background) Scanning-tunneling-microscopy image of graphite, a well-established lubricant at macroscopic length scales. Courtesy of M. Rose

Michael Rose contributed to the cover design.

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